Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/663,671	MIYAIRI ET AL.	
Examiner	Art Unit	
Felisa C. Hiteshew	1722	

	CEAD	CHED	
SEARCHED			
Class	Subclass	Date	Examiner
117	7	3/2/2006	F.H.
117	10	3/2/2006	F.H.
117	89	3/2/2006	F.H.
117	904	3/2/2006	F.H.
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		- · · -	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
STN (hcaplus, inspec, japio, uspatall, inpadoc)	3/2/2006	F.H.
Inventors' Name Search	3/2/2006	F.H.
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